United States Patent [19]

Yamamoto et al.

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[45] **Date of Patent: ** Aug. 7, 1984**

[54] **MICROMETER**

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[73] Assignee: **Mitutoyo Mfg. Co., Ltd.,** Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **367,711**

[22] Filed: **Apr. 12, 1982**

[30] **Foreign Application Priority Data**

Oct. 15, 1981 [JP] Japan 56-45848

[52] **U.S. Cl.** **D10/73**

[58] **Field of Search** .... D10/73; 33/166 R, 172 R; 116/284, 285

[56] **References Cited**

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Attorney, Agent, or Firm—Flynn, Thiel, Boutell & Tanis

[57] **CLAIM**

The ornamental design for the micrometer, as shown.

DESCRIPTION

FIG. **1** is a front and top-left perspective view of a micrometer showing our new design;

FIG. **2** is a front elevational view thereof;

FIG. **3** is a rear elevational view thereof;

FIG. **4** is a top plan view thereof;

FIG. **5** is a bottom plan view thereof;

FIG. **6** is a left side elevational view thereof; and,

FIG. **7** is a right side elevational view thereof.

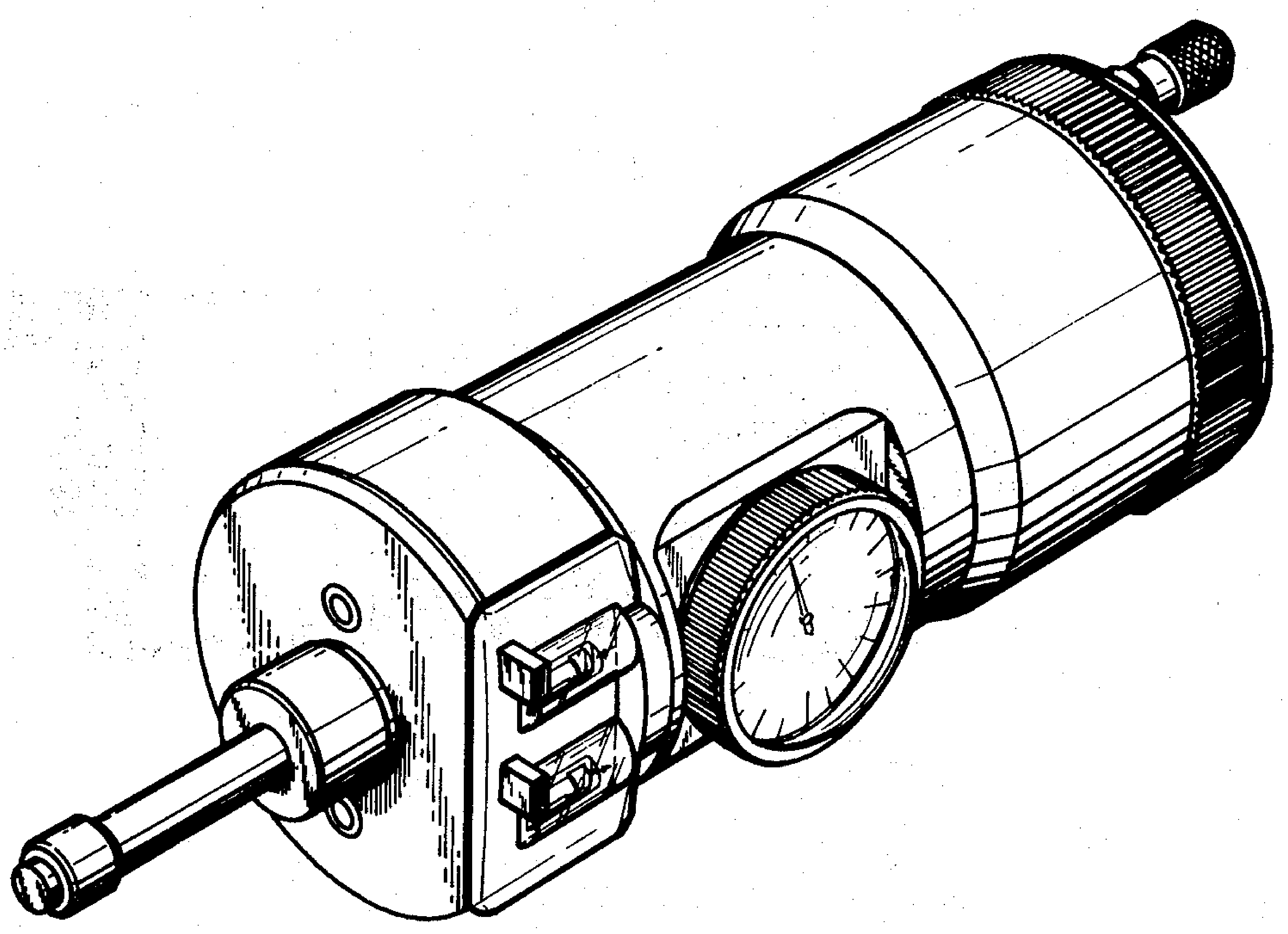

FIG. 1

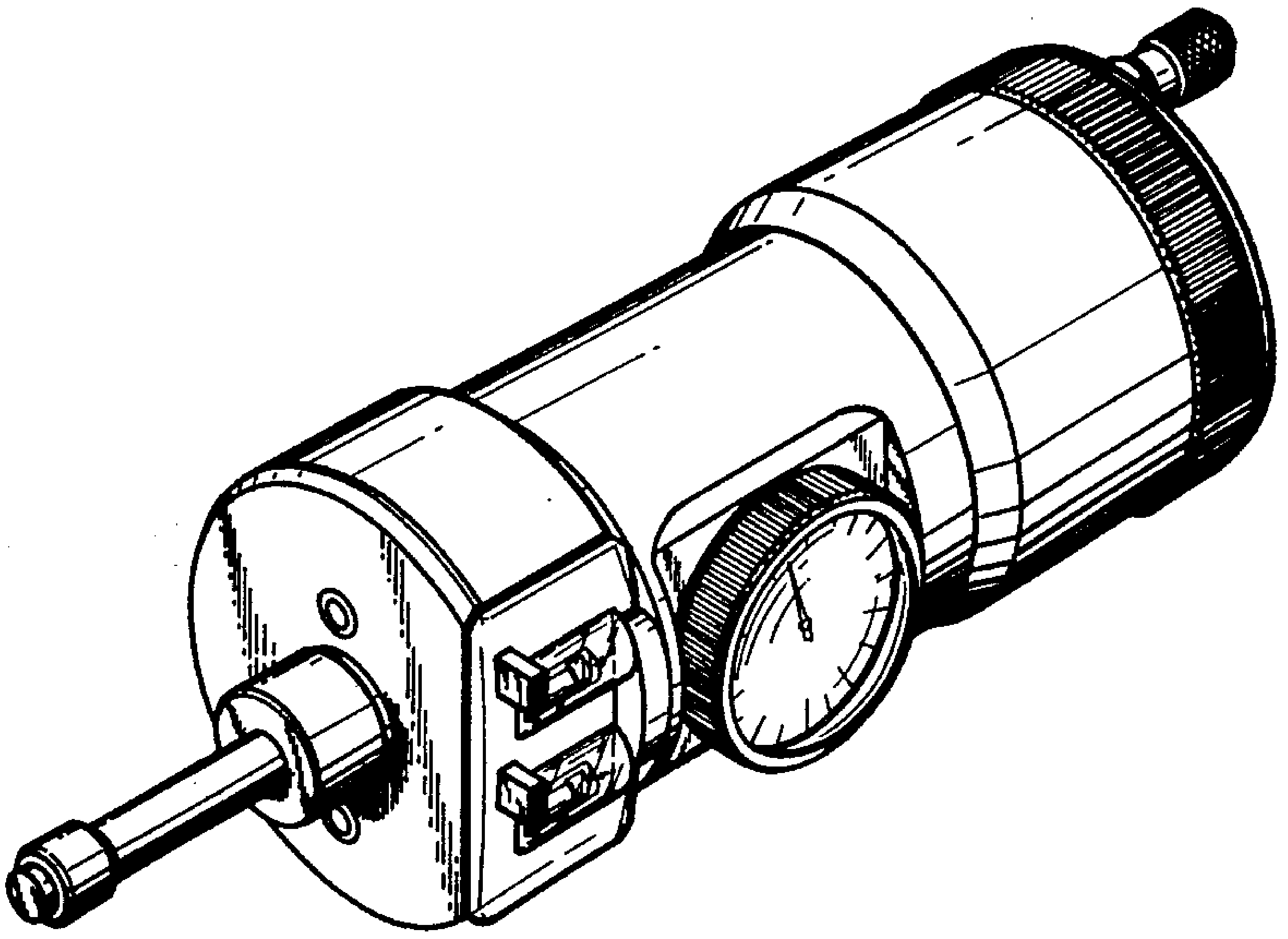

FIG. 2

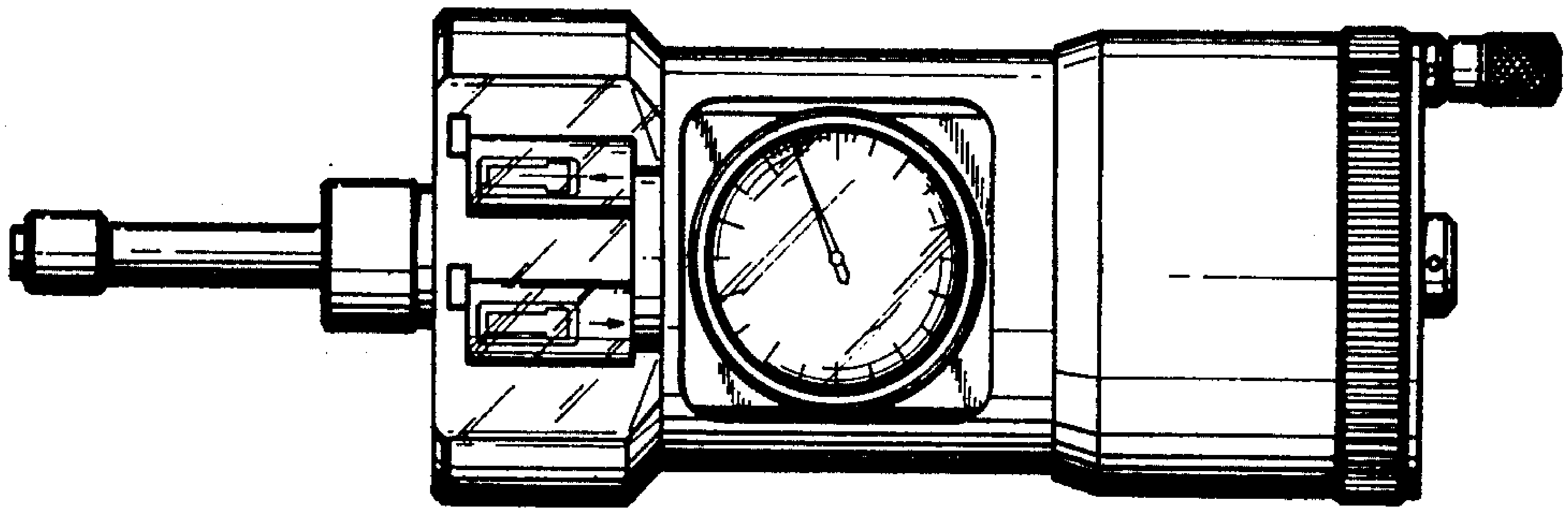

FIG. 3

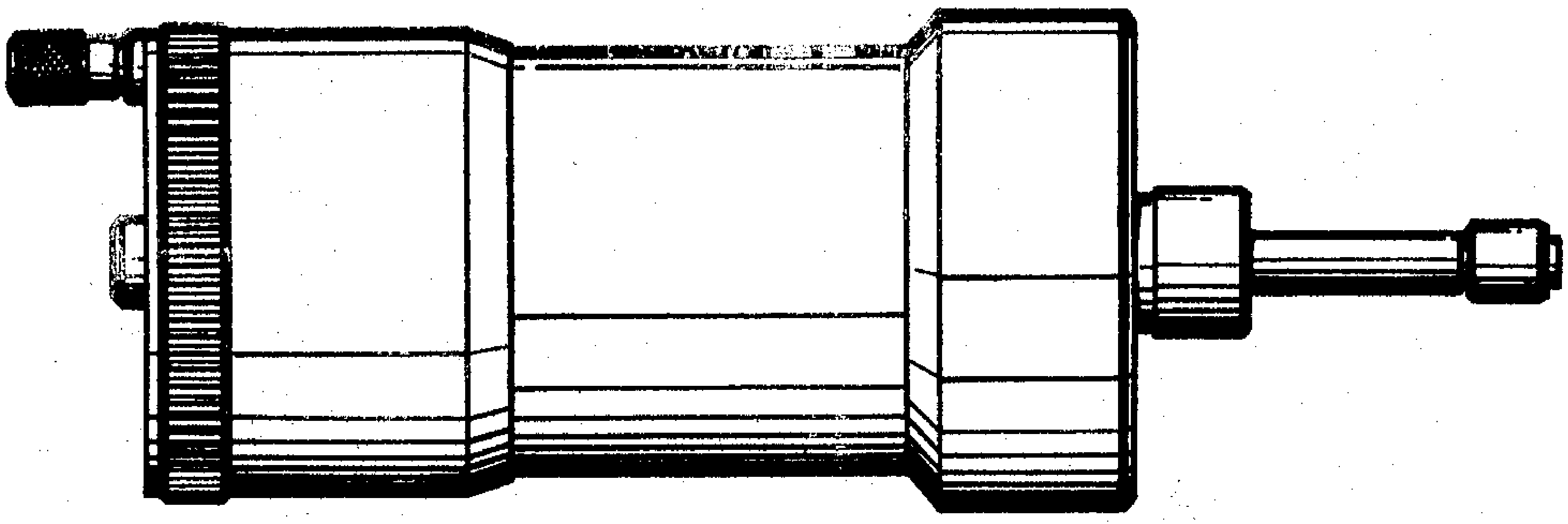

FIG. 4

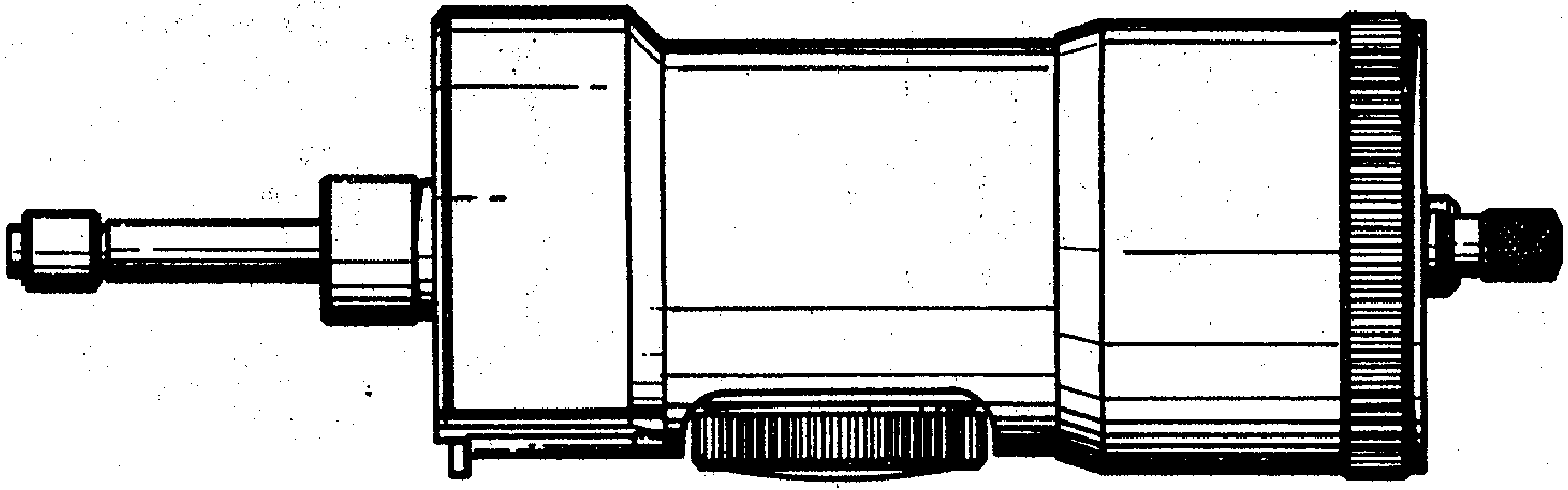

FIG. 5

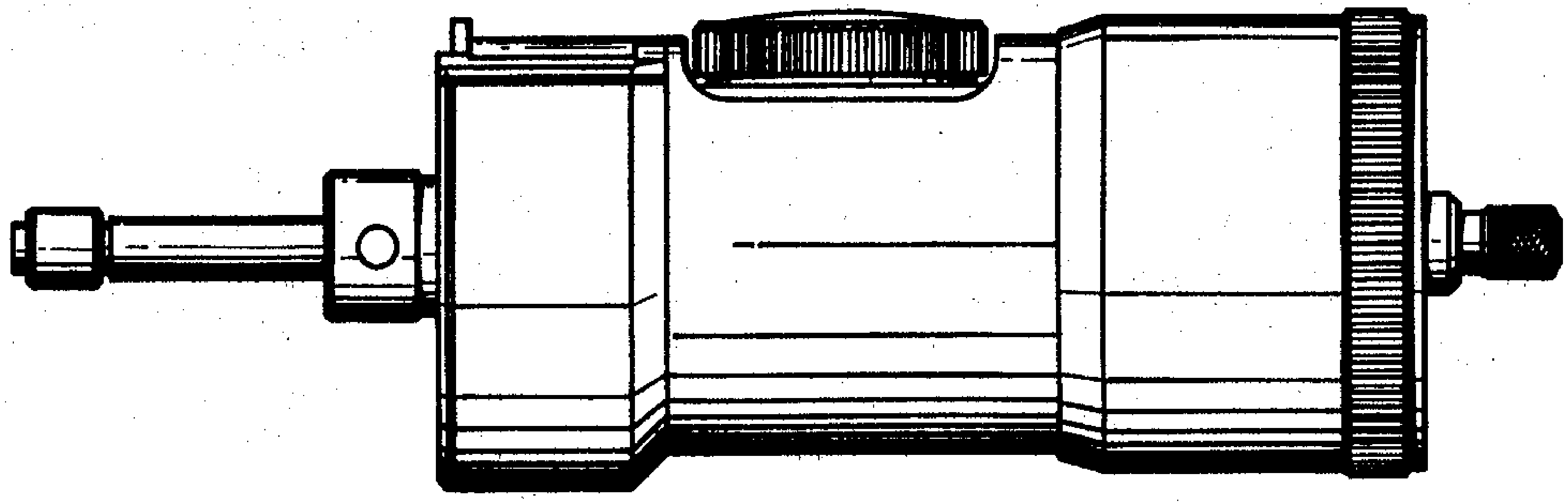

FIG. 6

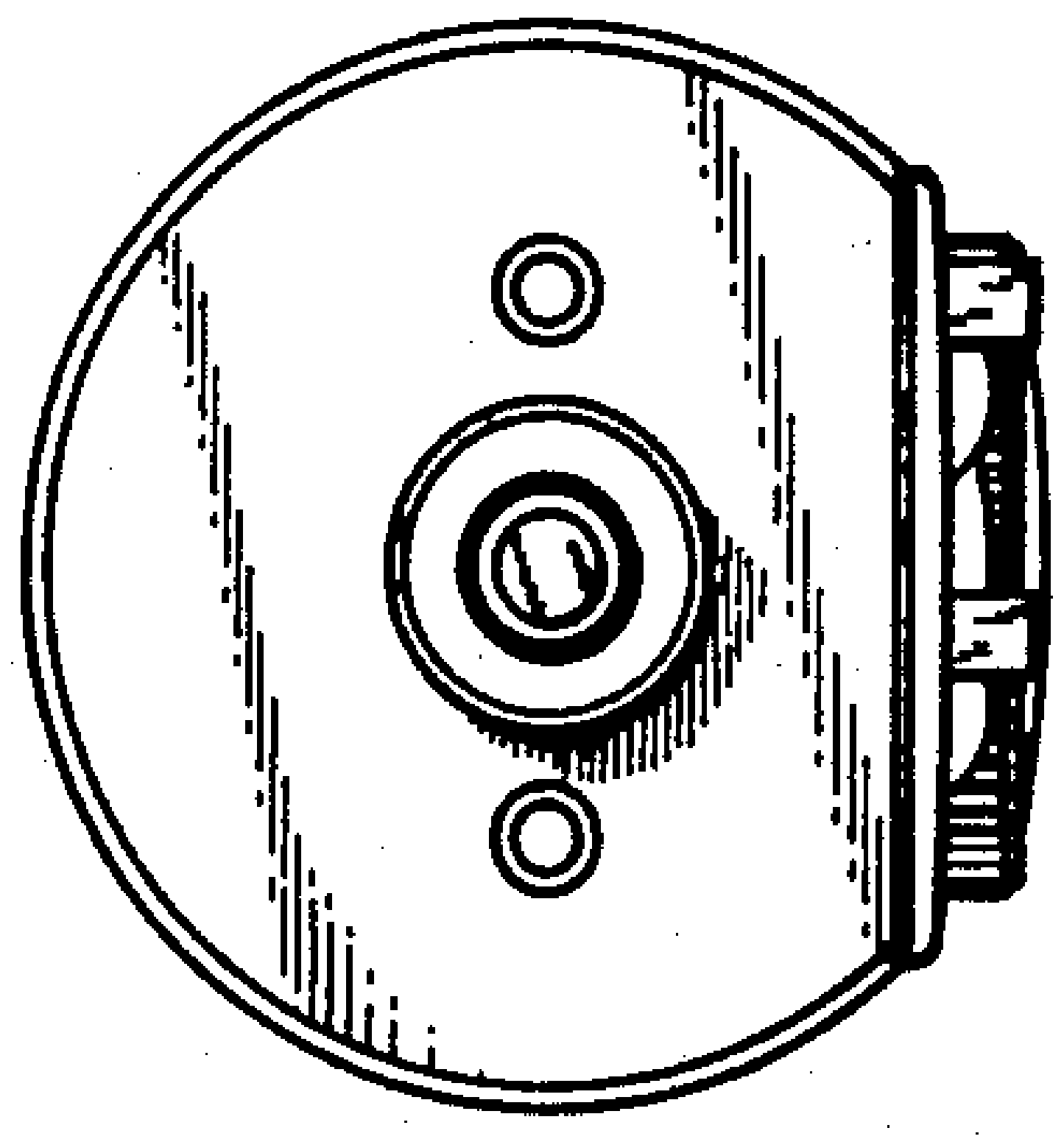

FIG. 7